

IFICLS (IFI Current Patent Legal Status Database)

Subject Coverage

- Reassigned U.S. patents from 1980 to the present
- Reexamined U.S. patents from 1981 to the present
- Extended U.S. patents from late 1985 to the present
- Expired U.S. patents from September 1985 to the present
- Reinstated U.S. patents from September 1985 to the present
- Adverse decision records from 1980 to the present
- Disclaimer/dedication records from 1980 to the present
- Reexamination request records from 1980 to the present
- Reissue request records from 1985 to the present
- Certificates of correction

File Type

Bibliographic

Features

Thesaurus	None				
Alerts (SDIs)	Weekly (default), monthly, bimonthly				
CAS Registry Number® Identifiers	<input type="checkbox"/>	Page Images	<input type="checkbox"/>	STN® AnaVist™	<input type="checkbox"/>
Keep & Share	<input checked="" type="checkbox"/>	SLART	<input type="checkbox"/>	STN Easy®	<input type="checkbox"/>
Learning Database	<input type="checkbox"/>	Structures	<input type="checkbox"/>		

Record Content

- Current legal status of U.S. patents. It includes reassigned patents (when the ownership of a patent is transferred from the original assignee to another company or individual), reexamined patents (patents that have undergone a review by the U.S. Patent and Trademark Office (USPTO) due to substantial new questions regarding the patentability of the patent's claims), patents extended beyond their normal 20-year term, expired patents, and reinstated patents.
- Adverse decision in interference, disclaimer/dedication information, reexamination request, reissue request, reissued patents, and certificate of correction.
- Patent number, former assignee, new assignee, reassignment type, e.g., full interest, date of reassignment, and reel and frame number of the USPTO microfilm record.
- Reexamination records include the patent number, patent assignee, name and location of the party requesting reexamination, reexamination request number and date, and reexamination certificate number and date. Text from the reexamination certificate describing the results of the reexamination is also included.
- Extension, expiration, and reinstatement records include the patent number, patent assignee, expiration, extension, or reinstatement date, and publication date of the *Official Gazette* of the USPTO containing the announcement of action.
- Reexamination request records include patent assignee, patent information, and reexamination request information. Adverse decision records include patent assignee, patent information, and adverse decision information. Disclaimer/dedication records include patent assignee, patent information, and disclaimer information. Reissue request records include patent assignee, patent information, reissue request information, and reissue patent numbers. Records for certificate of correction include patent assignee, patent information, and correction date.

File Size

More than 5.4 million records (08/19)

Coverage

1980-present

Updates Updated weekly

Language English

Database Producer IFI CLAIMS® Patent Services, a division of Fairview Reseach LLC
P.O. Box 1148, Madison, CT 06443
Phone: (203) 779-5301
Fax: (203) 583-4521
Email: info@ificlaims.com

Sources The U.S. Patent and Trademark Office

User Aids

- Online Helps (HELP DIRECTORY lists all help messages available)
- STNGUIDE

Clusters

- ALLBIB
- HPATENTS
- PATENTS

[STN Database Clusters](#) information (PDF).

Related Databases

- IFIALL
- IFIREF

Pricing Enter HELP COST at an arrow prompt (=>).

SEARCH and DISPLAY Field Codes

There are no fields that allow left truncation.

Search Field Name	Search Code	Search Examples	Display Codes
Basic Index (contains single words from the adverse decision text (ADTX), disclaimer/dedication text (DDTX), and patent claim text for reexamined patents (CLM) fields)	None (or /BI)	S ALKOXY? S ALKYL RADICAL# S DISCLAIMER#	ADTX, CLM, DDTX
Accession Number	/AN	S 1878343/AN	AN
Adverse Decision Date (1)	/ADD	S APR 7, 2005/ADD	ADD
Adverse Decision Number	/ADN	S 103473/ADN	ADN
Correction Date (1)	/CDAT	S 20040601/CDAT	CDAT
Disclaimer/Dedication Date (1)	/DDD	S 20010904/DDD	DDD
Document Type (code and text)	/DT (or /TC)	S EXPIRED/DT S XP/DT	DT
Entry Date (1)	/ED	S 20040511/ED	Not displayed
Expiration Date (1)	/XPD	S 20020700-20031100/XPD	XPD
Extension Date (1)	/XTD	S XTD> 19940401	XTD
Field Availability	/FA	S CLM/FA	Not displayed
Language (code and text)	/LA	S ENGLISH/LA	Not displayed
Official Gazette Issue Date with Adverse Decision (1)	/ADG	S 20050222/ADG	ADG
Official Gazette Issue Date with Disclaimer/Dedication Date (1)	/DDG	S NOV 13 2001/DDG	DDG
Official Gazette Issue Date with Expiration Announcement (1)	/XPG	S XPG>19970901 S XPG>SEP 1, 1997	XPG
Official Gazette Issue Date with Extension Announcement (1)	/XTG	S XTG>19950900	XTG
Official Gazette Issue Date with Reexamination Request (1)	/RQG	S 19960903/RQG	RQG
Official Gazette Issue Date with Reinstatement Announcement (1)	/RIG	S RIG>=19971123 S RIG>=NOV 23, 1997	RIG
Official Gazette Issue Date with Reissue Request (1)	/REG	S 19951205/REG	REG
Patent Assignee (2)	/PA (or /CS)	S KODAK/PA S DOW CORNING/PA	PA, RAC
Patent Assignee, Original (2,3)	/PAO	S BRAUN/PAO	PAO
Patent Country	/PC	S US/PC	PI
Patent Number (4,5)	/PN	S US4893422/PN S US33420/PN	PI, PN
Publication Date (1)	/PD	S 19900116/PD	PI
Publication Year (1)	/PY	S PY>=1997	PI
Reassignment Address (2)	/RAA	S KENYON/RAA	RAA
Reassignment Company (2)	/RAC	S UPJOHN/RAC	RAC
Reassignment Date (1)	/RAD	S 20030811/RAD	RAD
Reassignment Kind (2)	/RAK	S FULL/RAK	RAK
Reexamination Certificate Date (1)	/RXD	S 19900410/RXD S RXD>=19920630	RXD
Reexamination Date (1)	/RRD	S 19920218/RRD	RRD
Reexamination Numbers	/RXN	S B14769435/RXN	RXN
Reexamination Request Date (1)	/RQD	S 19960802/RQD	RQD
Reexamination Request Number	/RQN	S 90/004321/RQN	RQN
Reexamination Request Requestor (2)	/RQR	S ELECTRA/RQR	RQR
Reexamination Requestor (2)	/RXR	S DOW CHEMICAL/RXR	RXR
Reinstatement Date (1)	/RID	S RID>19930500	RID
Reissue Examination Group	/REX	S 1107/REX	REX

SEARCH and DISPLAY Field Codes (cont'd)

Search Field Name	Search Code	Search Examples	Display Codes
Reissue Request Date (1) Reissue Request Number Update Date (1) Update Date, Correction Data (latest IFI update to Correction Data) (1) Update Date, Reassignment Data (latest IFI update to Reassignment Data) (1) Update Date, Status Information (latest IFI update to the Status Information) (1,6)	/RED /RRN /UP /UPCD /UPRAI /UPSTA	S 20040213/RED S 06/026465/RRN S 20040420/UP S 19990703/UPCD S 20010320/UPRAI S 19990720/UPSTA	RED RRN Not displayed UPCD UPRAI UPSTA

(1) Numeric search field that may be searched with numeric operators or ranges.

(2) Search with implied (S) proximity is available in this field.

(3) This field contains data only for reassigned patents.

(4) Either STN or Derwent format may be used.

(5) Reissue patent numbers are searchable in the field.

(6) This field contains the latest IFI update to the Status Information other than Certificate of Correction or Reassignment Actions. This includes Expirations, Extensions, Reinstatements, Adverse Decisions, Disclaimer/Dedications, Request for Reexamination, Requests for Reissue, and Reexaminations.

Super Search Fields

Enter a super search code to perform a search in one or more fields that may contain the desired information. Super search fields facilitate crossfile and multifile searching. EXPAND may not be used with super search fields. Use EXPAND with the individual field code instead.

Search Field Name	Search Code	Fields Searched	Search Examples	Display Codes
Patent Assignee Group Patent Countries Patent Numbers (1,2)	/PASS /PCS /PATS	/PA, /PAO, /RAC /DS, /FC, /PC /FN, /PN	S MIT/PASS S US/PCS S US4893422/PATS	PASS PI PI, PN

(1) Either STN or Derwent format may be used.

(2) Reissue patent numbers are searchable in the field.

DISPLAY and PRINT Formats

Any combination of formats may be used to display or print answers. Multiple codes must be separated by commas or spaces, e.g., D L3 1-10 PI,PA or D L3 1-10 PI PA. The fields are displayed or printed in the order requested.

Hit-term highlighting is available in AND, ADTX, CDAT, CLM, DDTX, DT, PA, RQN, RRN, and RXN. Highlighting is set ON by default and must be ON when SEARCH is performed in order to use the HIT, KWIC, and OCC formats.

Format	Content	Examples
AN (1) ADD ADG AND ADTX CDAT CLM DDD DDG DDTX DT (TC) PA (CS) PAO PI (1) PN (1) RAA RAC RAD RAK RED REG REX RID RIG RQD RQG RQN RQR RRD RRN RXD RXN RXR UPCD (1,2) UPRAI (1,2) UPSTA (1,2) XPD XPG XTD XTG	Accession Number Adverse Decision Date Official Gazette Issue Date with Adverse Decision Adverse Decision Number Adverse Decision Text Correction Date Patent Claim Text Disclaimer/Dedication Date Official Gazette Issue Date with Disclaimer/Dedication Date Disclaimer/Dedication Text Document Type Patent Assignee Patent Assignee, Original Patent Information Patent Information and Reissue Patent Number Reassignment Address Reassigned Country Reassignment Date Reassignment Kind Reissue Request Date Official Gazette Issue Date with Reissue Request Reissue Examination Group Reinstatement Date Official Gazette Issue Date with Reinstatement Announcement Reexamination Request Date Official Gazette Issue Date with Reexamination Request Reexamination Request Number Reexamination Request Requestor Reexamination Request Date Reissue Request Number Reexamination Certificate Date Reexamination Numbers Reexamination Requestor Update Date, Correction Data Update Date, Reassignment Information Update Date, Status Information Expiration Date Official Gazette Issue Date with Expiration Announcement Extension Date Official Gazette Issue Date with Extension Announcement	D L4 5 AN D 1,3 ADD D ADG 1-5 D AND D ADTX D CDAT D 7 CLM D DDD D DDG D DDTX D 1-4 DT D L2 1-3 PA D PA, PAO D 1,5,10 PI D PN D RAA D 3-6 RAC D L4 RAD D RAK D RED D REG D REX D RID D RIG D RQD L1 D RQG D RQN D RQR 1-3 D 2,4,6 RRD D RRN D 2-4,10 RXD D RXN D RXR D UPCD D UPRAI D UPSTA D 4 XPD D XPG D XTD D XTG
ABS ADI ALL	CLM Adverse Decision Information (AND, ADD, ADG, ADTX) AN, PA, PI, DT, CDAT, RID, RIG, XPD, XPG, XTD, XTG, RXI (RXR, RXN, RRD, Certificate Number, RXD), RAI (RAD, RAK, PAO, RAC, RAA), ADI (AND, ADD, ADG, ADTX), DDI (DDD, DDG, DDTX), RQI (RQR, RQN, RQD, RQG), REI (RRN, RED, REG, REX, PN), CLM	D L2 ABS D L1 ADI 1-2 D 3 ALL

DISPLAY and PRINT Formats (cont'd)

Format	Content	Examples
BIB (STD)	AN, PA, PI, DT, CDAT, RID, RIG, XPD, XPG, XTD, XTG, RXI (RXR, RXN, RRD, Certificate Number, RXD), RAI (RAD, RAK, PAO, RAC, RAA), ADI (AND, ADD, ADG, ADTX), DDI (DDB, DDG, DDTX), RQI (RQR, RQN, RQD, RQG), REI (RRN, RED, REG, REX, PN) (BIB is the default)	D 1,8 BIB
CBIB	Compressed bibliographic information	D L1 CBIB 2
DDI	Disclaimer/Dedication Information (DDD, DDG, DDTX)	D DDI
IALL	ALL, indented with text labels	D IALL
IBIB	BIB, indented with text labels	D IBIB
ISTD	STD, indented with text labels	D ISTD 1-5
PASS	PA, PAO, RAC	D PASS
RAI	Reassignment Information (RAD, RAK, PAO, RAC, RAA)	D L1 RAI
REI	Reissue Request Information (RRN, RED, REG, REX, PN)	D REI
RQI	Reexamination Request Information (RQR, RQN, RQD, RQG)	D RQI
RXI	Reexamination Information (RXR, RXN, RRD, RXD)	D RXI
STD	BIB	D 1,8 STD
TRIAL (TRI) (1)	AN, PI	D 1-5 TRIAL
HIT	Fields containing hit terms	D HIT
KWIC	Hit terms with 20 words on either side (KeyWord-In-Context)	D KWIC
OCC (1)	Number of occurrences of hit terms and fields in which they occur	D OCC 1-10

(1) No online display fee for this format.

(2) Custom display only.

SELECT, ANALYZE, and SORT Fields

The SELECT command is used to create E-numbers containing terms taken from the specified field in an answer set.

The ANALYZE command is used to create an L-number containing terms taken from the specified field in an answer set.

The SORT command is used to rearrange the search results in either alphabetic or numeric order of the specified field(s).

Field Name	Field Code	ANALYZE/ SELECT (1)	SORT
Accession Number	AN	Y (2)	N
Adverse Decision Date	ADD	Y (2)	Y
Adverse Decision Number	ADN	Y	Y
Adverse Decision Text	ADTX	Y (3)	N
Claim Text	CLM	Y (3)	N
Corporate Source	CS	Y	Y
Correction Date	CDAT	Y (2)	Y
Disclaimer/Dedication Date	DDD	Y (2)	Y
Disclaimer/Dedication Text	DDTX	Y (3)	N
Document Type	DT	Y	Y
Expiration Date	XPD	Y (2)	Y
Extension Date	XTD	Y (2)	Y
Official Gazette Issue Date with Adverse Decision	ADG	Y (2)	Y
Official Gazette Issue Date with Disclaimer/Dedication Date	DDG	Y (2)	Y
Official Gazette Issue Date with Expiration Announcement	XPG	Y (2)	Y
Official Gazette Issue Date with Extension Announcement	XTG	Y (2)	Y
Official Gazette Issue Date with Reexamination Request	RQG	Y (2)	Y
Official Gazette Issue Date with Reinstatement Announcement	RIG	Y (2)	Y
Official Gazette Issue Date with Reissue Request	REG	Y (2)	Y

SELECT, ANALYZE, and SORT Fields (cont'd)

Field Name	Field Code	ANALYZE/ SELECT (1)	SORT
Patent Assignee	PA	Y	Y
Patent Assignee Group	PASS	Y	N
Patent Assignee, Original	PAO	Y (2)	Y
Patent Countries	PCS	Y (2,4)	N
Patent Country	PC	Y (2)	Y
Patent Information	PI	Y (2,5)	Y
Patent Number	PN	Y (2,6) (default)	Y
	PATS	Y (2,6)	N
Publication Date	PD	Y (2)	Y
Publication Year	PY	Y (2)	Y
Reassignment Agent	RAA	Y (2)	Y
Reassignment Company	RAC	Y (2)	Y
Reassignment Date	RAD	Y (2)	Y
Reassignment Kind	RAK	Y (2)	Y
Reexamination Certificate Date	RXD	Y (2)	Y
Reexamination Date	RRD	Y (2)	Y
Reexamination Number	RXN	Y	Y
Reexamination Request Date	RRD	Y (2)	Y
Reexamination Requester	RXR	Y (2)	Y
Reexamination Request Date	RQD	Y (2)	Y
Reexamination Request Number	RQN	Y	Y
Reexamination Request Requestor	RQR	Y (2)	Y
Reinstatement Date	RID	Y (2)	Y
Reissue Examination Group	REX	Y (2)	Y
Reissue Request Date	RED	Y (2)	Y
Reissue Request Number	RRN	Y	Y
Treatment Code	TC	Y	Y
Update Date, Correction Data	UPCD	Y (2)	Y
Update Date, Reassignment Information	UPRAI	Y (2)	Y
Update Date, Status Information	UPSTA	Y (2)	Y

- (1) HIT may be used to restrict terms extracted to terms that match the search expression used to create the answer set, e.g., SEL HIT PA.
- (2) SELECT HIT and ANALYZE HIT are not valid with this field.
- (3) Appends /BI to the terms created by SELECT.
- (4) Selects or analyzes PC with /PCS appended to the terms created by SELECT.
- (5) Selects or analyzes the patent number with /PN appended to the terms created by SELECT.
- (6) Selects or analyzes the patent and reissue patent numbers with /PN appended to the terms created by SELECT.
- (7) Selects or analyzes the patent and reissue patent numbers with /PATS appended to the terms created by SELECT.

Sample Records

DISPLAY IALL (Reexamined Patent)

ACCESSION NO.: 4047461 IFICLS
 PATENT ASSIGNEE: International Business Machines Corp
 PATENT INFORMATION: US 6718445 20040406
 DOCUMENT TYPE: REEXAMINED; REEXAMINATION REQUESTED;
 CERTIFICATE OF CORRECTION
 CORRECTION DATE: 5 Jul 2005
 REEXAMINATION REQUEST:
 REQUESTOR: International Business Machines Corporation, Armonk, NY
 REQUEST NUMBER: 90/007210
 REQUEST DATE: 20040917
 OG DATE: 20041102
 REQUESTOR: International Business Machines Corporation, Armonk, NY
 REQUEST NUMBER: 90/007134
 REQUEST DATE: 20041014
 OG DATE: 20041203
 REEXAMINATION INFO.:
 REQUESTOR: International business Machines Corporation Armonk, NY
 US
 REQUEST NUMBER: 90/007134
 REQUEST DATE: 20041014
 CERTIFICATE NUMBER: C16718445 (5170th)
 CERTIFICATE DATE: 20050802

CLAIM

AS A RESULT OF REEXAMINATION, IT HAS BEEN DETERMINED THAT: The patentability of claims 1-19 is confirmed. 1. A buffer management system comprising: a buffer pool further comprised of an amount of fixed storage and an amount of virtual storage; a target maximum fixed value for the amount of fixed storage, the target maximum fixed value dynamically alterable by a system administrator; a target maximum virtual value for the amount of virtual storage, the target maximum virtual value dynamically alterable by a system administrator; and a buffer manager for dynamically varying the amount of fixed storage and the amount of virtual storage based on a comparison of present usage of the amount of fixed storage and the amount of virtual storage to target maximum fixed and target maximum virtual values.

DISPLAY IALL (Reassigned Patent)

ACCESSION NO.: 4297251 IFICLS
 PATENT ASSIGNEE: Wilson, William F
 PATENT INFORMATION: US 6945423 20050920
 DOCUMENT TYPE: REASSIGNED
 REASSIGNMENT INFO.:
 DATE: 20050214
 KIND: ASSIGNMENT OF ASSIGNORS INTEREST
 ASSIGNOR: WILSON, WILLIAM, DATE SIGNED: 10/04/2004
 ASSIGNEE: SURGE CONTROL, LLC, 3910 S. INDUSTRIAL AVE., COEUR D'
 ARLENE, IDAHO, 83815
 AGENT: MICHAEL S. SMITH, BLACK LOWE & GRAHAM, PLLC, 701 FIFTH
 AVENUE, SUITE 4800, SEATTLE, WA 98104
 MICROFILM REEL NO: 016264
 MICROFILM FRAME NO: 0279

DISPLAY IALL (Expired Patent)

ACCESSION NO.: 2613100 IFICLS
 PATENT ASSIGNEE: Stellmach, Robert N
 PATENT INFORMATION: US 5423083 19950606
 DOCUMENT TYPE: EXPIRED
 EXPIRED INFO.: 19990606 OG DATE: 19990803

DISPLAY IALL (Reinstated Patent)

ACCESSION NO.: 2048875 IFICLS
PATENT ASSIGNEE: Testing Machines Inc
PATENT INFORMATION: US 4928533 19900529
DOCUMENT TYPE: EXPIRED; REINSTATED
EXPIRED INFO.: 19940529 OG DATE: 19940809
REINSTATEMENT INFO.: 19940803 OG DATE: 19941004

DISPLAY ALL (Extended Patent)

ACCESSION NO.: 2475348 IFICLS
PATENT ASSIGNEE: Procter & Gamble Co The
PATENT INFORMATION: US 34617 19940524
DOCUMENT TYPE: EXTENDED
EXTENDED INFO.: DATE: 19941201 DESC: (One-year) OG DATE: 19950214
DATE: 19950214 DESC: (Nine (9) months) OG DATE:
19970225
DATE: 19960312 DESC: (One year) OG DATE: 19960312
DATE: 19981023 DESC: (two years) OG DATE: 19981201
ORIG. EXPIRATION DATE: 19960212, NEW EXPIRATION DATE:
19980130
TRADE NAME: OLEAN (olestra)

DISPLAY IALL (Adverse Decision)

ACCESSION NO.: 3286429 IFICLS
PATENT ASSIGNEE: TruTek Inc.
PATENT INFORMATION: US 5697929 19971216
DOCUMENT TYPE: ADVERSE DECISION
ADVERSE DECISION IN INTERFERENCE:
INTERFERENCE NO: 104708
DECISION DATE: 20031126
OG DATE: 20030114
CLAIMS AFFECTED: as to claims 1, 3-8 and 10-14.

DISPLAY IALL (Disclaimer/Dedication)

ACCESSION NO.: 3804778 IFICLS
PATENT ASSIGNEE: Applied materials Inc.
PATENT INFORMATION: US 6579426 20030617
DOCUMENT TYPE: DISCLAIMER/DEDICATION
DISCLAIMER INFO.:
DATE: 20030610
OG DATE: 20031111
TEXT: The term of this patent shall not extend beyond the
expiration date of Pat. No. 6,254,738.

DISPLAY IALL (Reexamination Requested)

ACCESSION NO.: 3523296 IFICLS
PATENT ASSIGNEE: Apcon Inc.ech Group Inc
PATENT INFORMATION: US 6243510 20010605
DOCUMENT TYPE: REEXAMINATION REQUESTED
REEXAMINATION REQUEST:
REQUESTOR: Apcon, Inc., Tualatin, OR.
REQUEST NUMBER: 90/006998
REQUEST DATE: 200404061
OG DATE: 20040518
OG DATE: 19990601

IFICLS**DISPLAY IALL (Reissue Request)**

ACCESSION NO.: 3108309 IFICLS
PATENT ASSIGNEE: Surgical Innovations LLC
PATENT INFORMATION: US 5868765 19990209
DOCUMENT TYPE: REISSUE REQUESTED
REISSUE REQUEST:
REQUEST NUMBER: 09/299449
REQUEST DATE: 19990426
OG DATE: 19990622
EXAMINATION GROUP: 3731
PATENT NUMBER: US 37107

DISPLAY ALL (Certificate of Correction)

ACCESSION NO.: 3131384 IFICLS
PATENT ASSIGNEE: NEC Corp JP
PATENT INFORMATION: US 5889744 19990330
DOCUMENT TYPE: CERTIFICATE OF CORRECTION
CORRECTION DATE: 1 Jun 1999

In North America

CAS
STN North America
P.O. Box 3012
Columbus, Ohio 43210-0012 U.S.A.

CAS Customer Center:
Phone: 800-753-4227 (North America)
614-447-3700 (worldwide)
Fax: 614-447-3751
Email: help@cas.org
Internet: www.cas.org

In Europe

FIZ Karlsruhe
STN Europe
P.O. Box 2465
76012 Karlsruhe
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Phone: +49-7247-808-555
Fax: +49-7247-808-259
Email: helpdesk@fiz-karlsruhe.de
Internet: www.stn-international.com

In Japan

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International Chemical Information)
STN Japan
Nakai Building
6-25-4 Honkomagome, Bunkyo-ku
Tokyo 113-0021, Japan
Phone: +81-3-5978-3601 (Technical Service)
+81-3-5978-3621 (Customer Service)
Fax: +81-3-5978-3600
Email: support@jaici.or.jp (Technical Service)
customer@jaici.or.jp (Customer Service)
Internet: www.jaici.or.jp